

MARKED UP VERSION OF REWRITTEN CLAIMS

6. (Amended) A probe for scanning probe lithography as claimed in claim 1,

wherein said [shaft] fine needle is made of a hard conductive material selected from the group consisting of titanium, tungsten, molybdenum, titanium carbide, tungsten carbide, molybdenum carbide, hydrogenated carbon, titanium nitride, tungsten nitride, molybdenum nitride, and carbon nanotube.

14. (Amended) A probe for scanning probe lithography as claimed in claim 1,

wherein said [shaft] fine needle is made of a hard conductive material selected from the group consisting of conductive diamond and chromium.